

STARPOWER

SEMICONDUCTOR

IGBT

GD800HFX120C6HA

1200V/800A 2 in one-package

General Description

STARPOWER IGBT Power Module provides ultra low conduction loss as well as short circuit ruggedness. They are designed for the applications such as hybrid and electric vehicle.

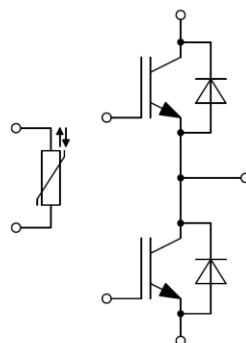
Features

- Low $V_{CE(sat)}$ Trench IGBT technology
- 10 μ s short circuit capability
- $V_{CE(sat)}$ with positive temperature coefficient
- Maximum junction temperature 175°C
- Low inductance case
- Fast & soft reverse recovery anti-parallel FWD
- Si₃N₄ substrate for low thermal resistance
- Isolated copper baseplate using Si₃N₄ AMB technology

Typical Applications

- Hybrid and electric vehicle
- Inverter for motor drive
- Uninterruptible power supply

Equivalent Circuit Schematic



Absolute Maximum Ratings $T_C=25^{\circ}\text{C}$ unless otherwise noted**IGBT**

Symbol	Description	Value	Unit
V_{CES}	Collector-Emitter Voltage	1200	V
V_{GES}	Gate-Emitter Voltage	± 20	V
I_C	Collector Current @ $T_C=100^{\circ}\text{C}$	800	A
I_{CM}	Pulsed Collector Current $t_p=1\text{ms}$	1600	A
P_D	Maximum Power Dissipation @ $T_j=175^{\circ}\text{C}$	5172	W

Diode

Symbol	Description	Value	Unit
V_{RRM}	Repetitive Peak Reverse Voltage	1200	V
I_F	Diode Continuous Forward Current	800	A
I_{FM}	Diode Maximum Forward Current $t_p=1\text{ms}$	1600	A

Module

Symbol	Description	Value	Unit
T_{jmax}	Maximum Junction Temperature	175	$^{\circ}\text{C}$
T_{jop}	Operating Junction Temperature	-40 to +150	$^{\circ}\text{C}$
T_{STG}	Storage Temperature Range	-40 to +125	$^{\circ}\text{C}$
V_{ISO}	Isolation Voltage RMS, $f=50\text{Hz}$, $t=1\text{min}$	2500	V

IGBT Characteristics $T_C=25^{\circ}\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$V_{CE(sat)}$	Collector to Emitter Saturation Voltage	$I_C=800\text{A}, V_{GE}=15\text{V}, T_j=25^{\circ}\text{C}$		1.95	2.40	V
		$I_C=800\text{A}, V_{GE}=15\text{V}, T_j=125^{\circ}\text{C}$		2.30		
		$I_C=800\text{A}, V_{GE}=15\text{V}, T_j=150^{\circ}\text{C}$		2.40		
$V_{GE(th)}$	Gate-Emitter Threshold Voltage	$I_C=24.0\text{mA}, V_{CE}=V_{GE}, T_j=25^{\circ}\text{C}$	5.6	6.2	6.8	V
I_{CES}	Collector Cut-Off Current	$V_{CE}=V_{CES}, V_{GE}=0\text{V}, T_j=25^{\circ}\text{C}$			1.0	mA
I_{GES}	Gate-Emitter Leakage Current	$V_{GE}=V_{GES}, V_{CE}=0\text{V}, T_j=25^{\circ}\text{C}$			400	nA
R_{Gint}	Internal Gate Resistance			0.7		Ω
C_{ies}	Input Capacitance	$V_{CE}=25\text{V}, f=1\text{MHz}, V_{GE}=0\text{V}$		62.1		nF
C_{res}	Reverse Transfer Capacitance			1.74		nF
Q_G	Gate Charge	$V_{GE}=-15 \dots +15\text{V}$		4.66		μC
$t_{d(on)}$	Turn-On Delay Time	$V_{CC}=600\text{V}, I_C=800\text{A}, R_G=1.0\Omega, V_{GE}=\pm 15\text{V}, L_S=40\text{nH}, T_j=25^{\circ}\text{C}$		266		ns
t_r	Rise Time			98		ns
$t_{d(off)}$	Turn-Off Delay Time			394		ns
t_f	Fall Time			201		ns
E_{on}	Turn-On Switching Loss			108		mJ
E_{off}	Turn-Off Switching Loss			73.8		mJ
$t_{d(on)}$	Turn-On Delay Time	$V_{CC}=600\text{V}, I_C=800\text{A}, R_G=1.0\Omega, V_{GE}=\pm 15\text{V}, L_S=40\text{nH}, T_j=125^{\circ}\text{C}$		280		ns
t_r	Rise Time			115		ns
$t_{d(off)}$	Turn-Off Delay Time			435		ns
t_f	Fall Time			275		ns
E_{on}	Turn-On Switching Loss			153		mJ
E_{off}	Turn-Off Switching Loss			91.3		mJ
$t_{d(on)}$	Turn-On Delay Time	$V_{CC}=600\text{V}, I_C=800\text{A}, R_G=1.0\Omega, V_{GE}=\pm 15\text{V}, L_S=40\text{nH}, T_j=150^{\circ}\text{C}$		282		ns
t_r	Rise Time			117		ns
$t_{d(off)}$	Turn-Off Delay Time			446		ns
t_f	Fall Time			290		ns
E_{on}	Turn-On Switching Loss			165		mJ
E_{off}	Turn-Off Switching Loss			94.4		mJ
I_{SC}	SC Data	$t_p \leq 10\mu\text{s}, V_{GE}=15\text{V}, T_j=150^{\circ}\text{C}, V_{CC}=800\text{V}, V_{CEM} \leq 1200\text{V}$		2400		A

Diode Characteristics $T_C=25^{\circ}\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V_F	Diode Forward Voltage	$I_F=800\text{A}, V_{GE}=0\text{V}, T_J=25^{\circ}\text{C}$		2.00	2.45	V
		$I_F=800\text{A}, V_{GE}=0\text{V}, T_J=125^{\circ}\text{C}$		2.15		
		$I_F=800\text{A}, V_{GE}=0\text{V}, T_J=150^{\circ}\text{C}$		2.20		
Q_r	Recovered Charge	$V_{CC}=600\text{V}, I_F=800\text{A},$ $-di/dt=5800\text{A}/\mu\text{s}, V_{GE}=-15\text{V},$ $L_S=40\text{nH}, T_J=25^{\circ}\text{C}$		48.1		μC
I_{RM}	Peak Reverse Recovery Current			264		A
E_{rec}	Reverse Recovery Energy			18.0		mJ
Q_r	Recovered Charge	$V_{CC}=600\text{V}, I_F=800\text{A},$ $-di/dt=4800\text{A}/\mu\text{s}, V_{GE}=-15\text{V},$ $L_S=40\text{nH}, T_J=125^{\circ}\text{C}$		95.3		μC
I_{RM}	Peak Reverse Recovery Current			291		A
E_{rec}	Reverse Recovery Energy			35.3		mJ
Q_r	Recovered Charge	$V_{CC}=600\text{V}, I_F=800\text{A},$ $-di/dt=4550\text{A}/\mu\text{s}, V_{GE}=-15\text{V},$ $L_S=40\text{nH}, T_J=150^{\circ}\text{C}$		107		μC
I_{RM}	Peak Reverse Recovery Current			293		A
E_{rec}	Reverse Recovery Energy			38.5		mJ

NTC Characteristics $T_C=25^{\circ}\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
R_{25}	Rated Resistance			5.0		k Ω
$\Delta R/R$	Deviation of R_{100}	$T_C=100^{\circ}\text{C}, R_{100}=493.3\Omega$	-5		5	%
P_{25}	Power Dissipation				20.0	mW
$B_{25/50}$	B-value	$R_2=R_{25}\exp[B_{25/50}(1/T_2-1/(298.15\text{K}))]$		3375		K
$B_{25/80}$	B-value	$R_2=R_{25}\exp[B_{25/80}(1/T_2-1/(298.15\text{K}))]$		3411		K
$B_{25/100}$	B-value	$R_2=R_{25}\exp[B_{25/100}(1/T_2-1/(298.15\text{K}))]$		3433		K

Module Characteristics $T_C=25^{\circ}\text{C}$ unless otherwise noted

Symbol	Parameter	Min.	Typ.	Max.	Unit
R_{thJC}	Junction-to-Case (per IGBT)			0.029	K/W
	Junction-to-Case (per Diode)			0.050	
R_{thCH}	Case-to-Heatsink (per IGBT)		0.028		K/W
	Case-to-Heatsink (per Diode)		0.049		
	Case-to-Heatsink (per Module)		0.009		
M	Terminal Connection Torque, Screw M6	3.0		6.0	N.m
	Mounting Torque, Screw M5	3.0		6.0	
G	Weight of Module		350		g

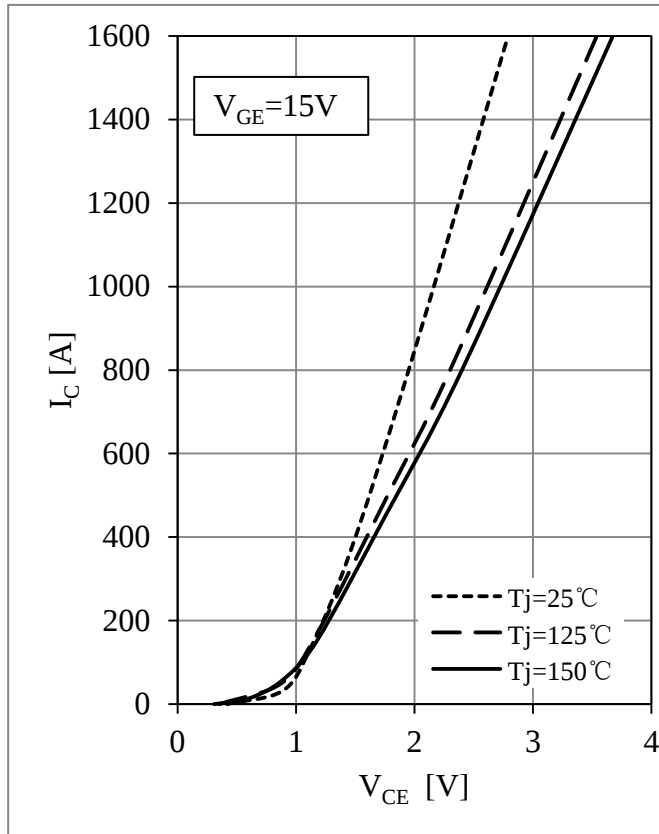


Fig 1. IGBT Output Characteristics

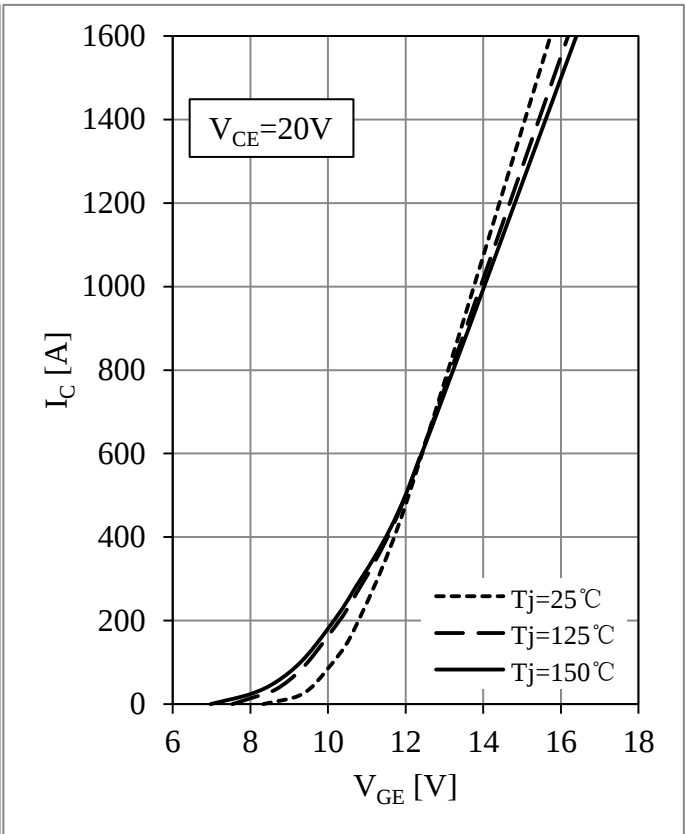
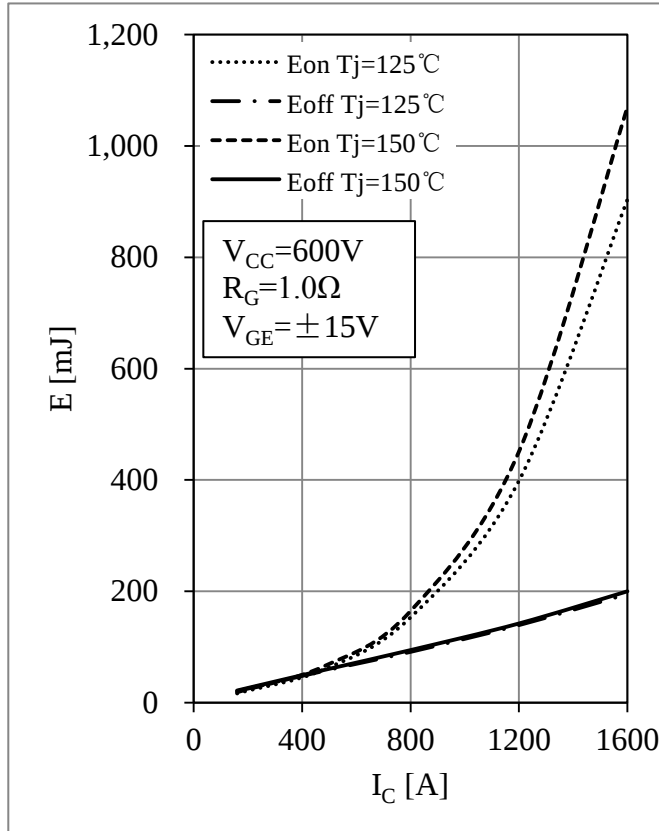
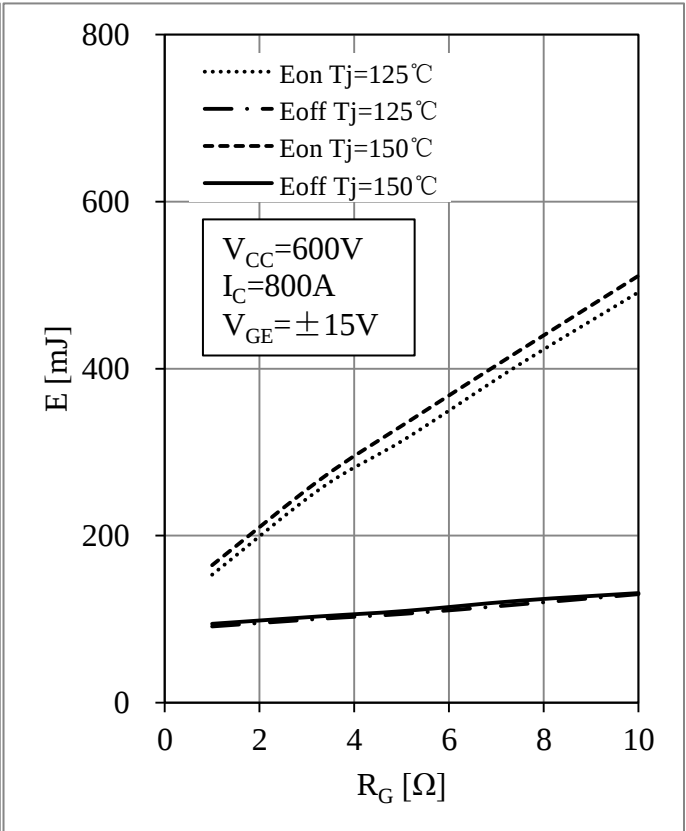


Fig 2. IGBT Transfer Characteristics

Fig 3. IGBT Switching Loss vs. I_C Fig 4. IGBT Switching Loss vs. R_G

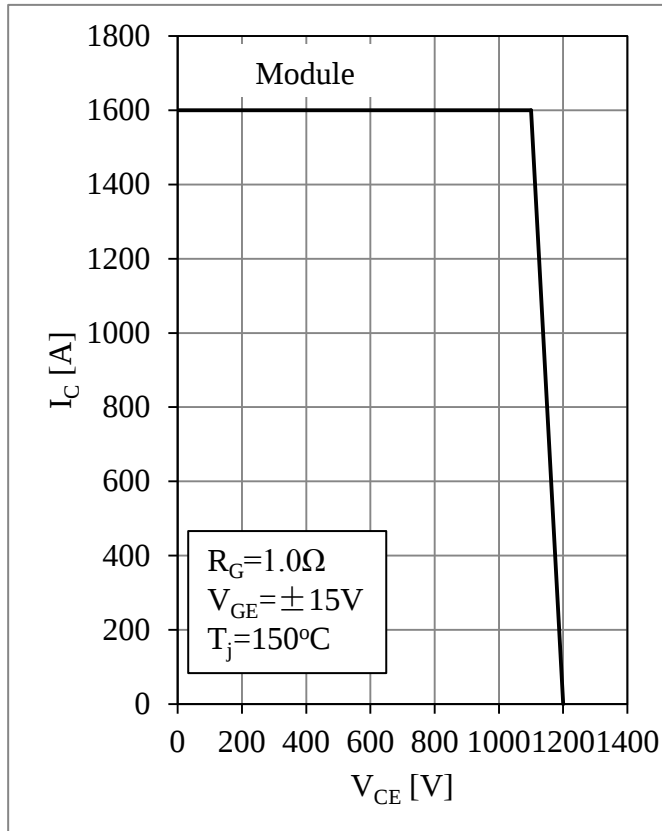


Fig 5. RBSOA

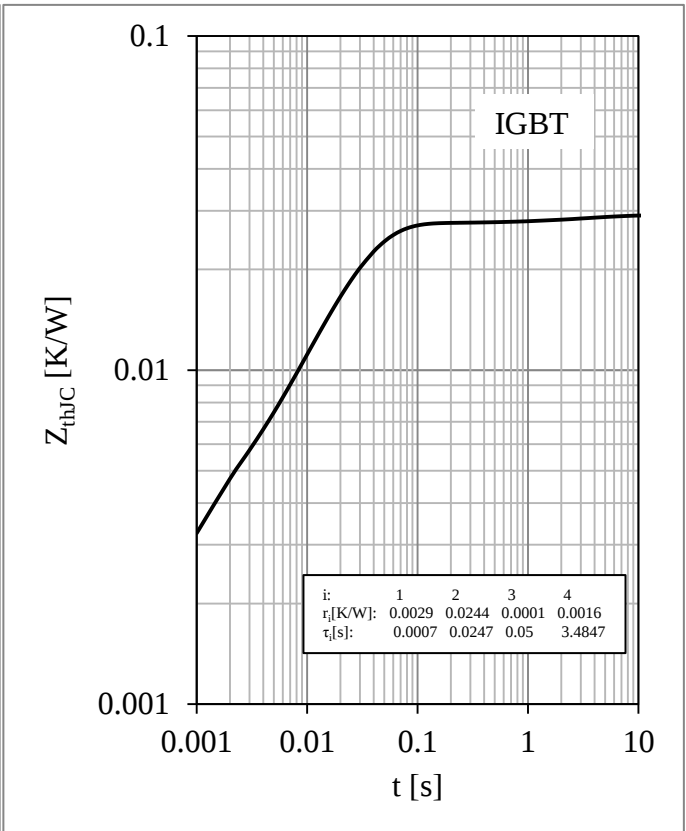


Fig 6. IGBT Transient Thermal Impedance

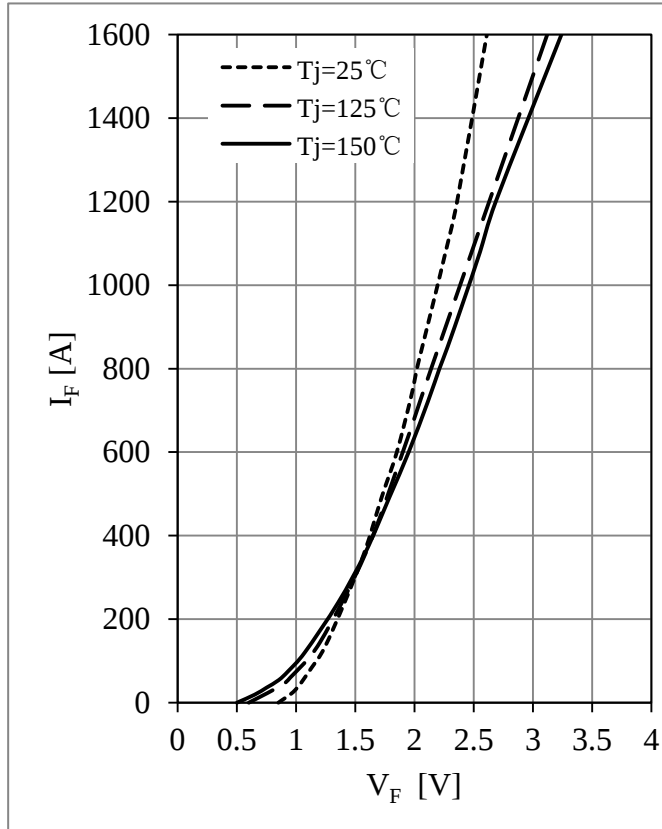
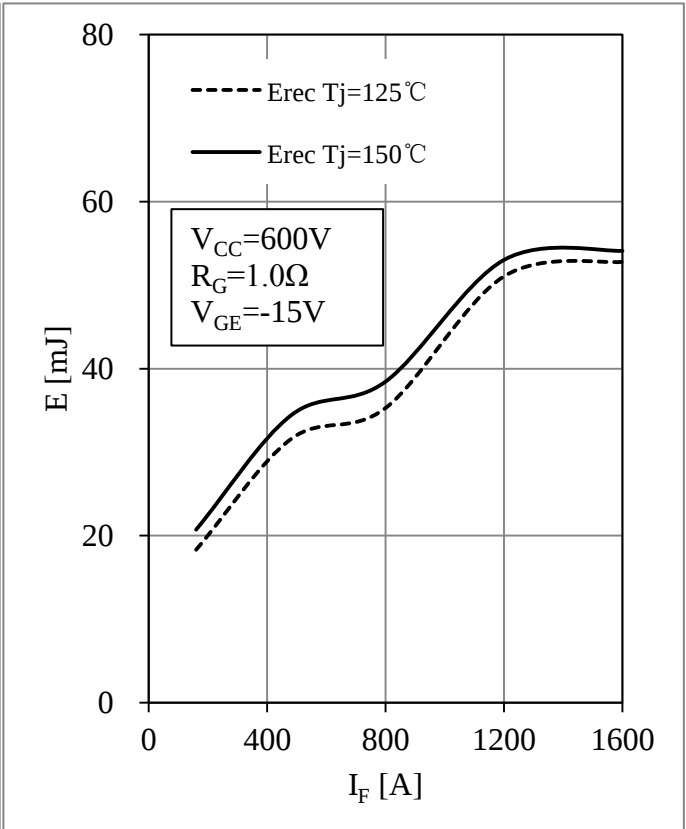


Fig 7. Diode Forward Characteristics

Fig 8. Diode Switching Loss vs. I_F

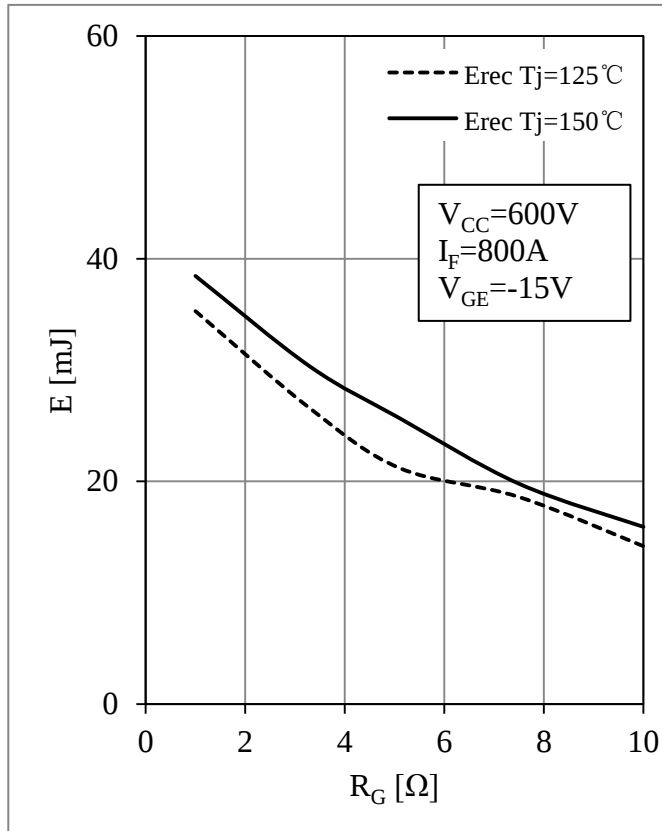
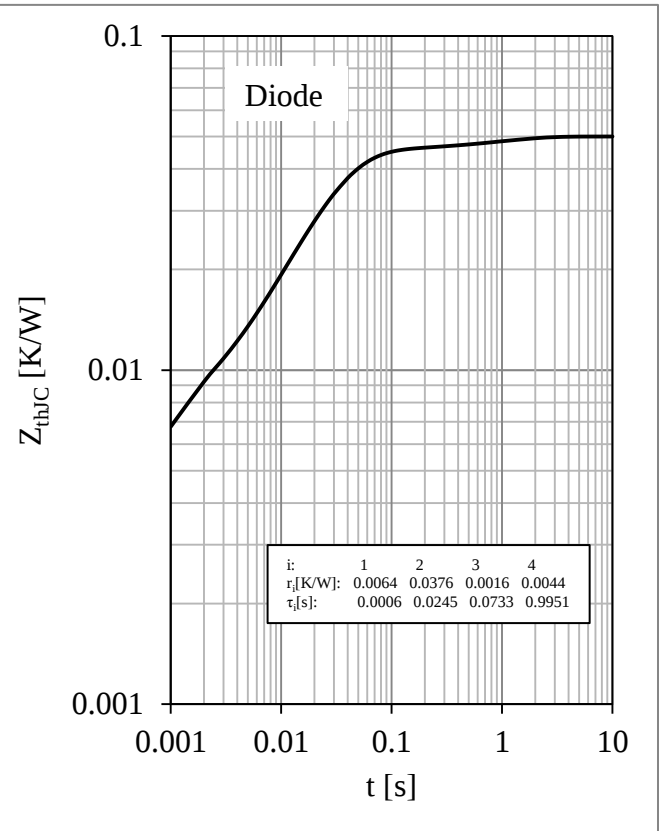
Fig 9. Diode Switching Loss vs. R_G 

Fig 10. Diode Transient Thermal Impedance

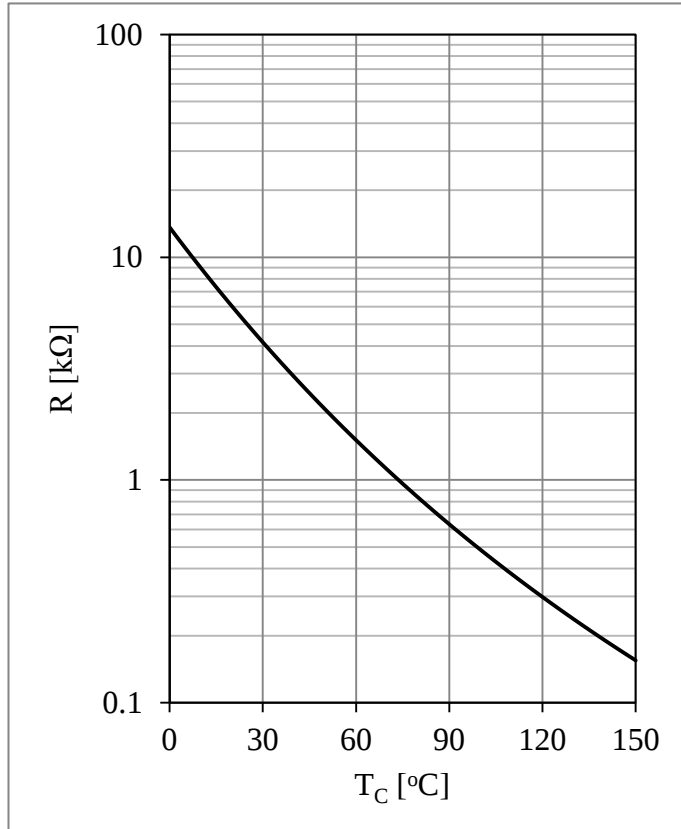
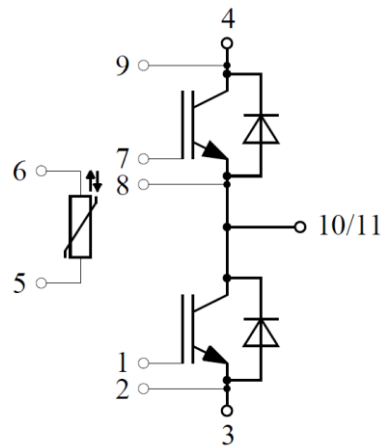


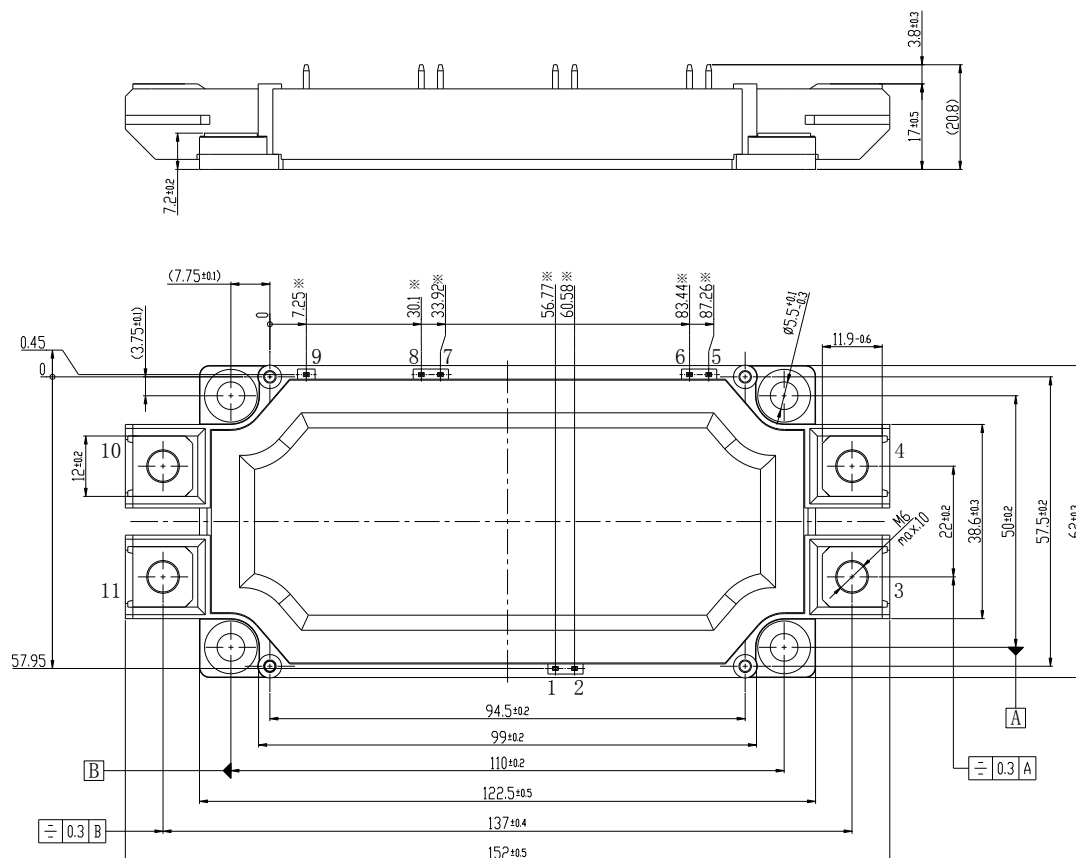
Fig 11. NTC Temperature Characteristic

Circuit Schematic



Package Dimensions

Dimensions in Millimeters



※: all dimensions with a tolerance of ± 0.5
dimensions valid in mounted condition

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